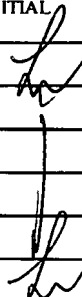


<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANTS PTO FORM 1449</b>	<b>ATTY. DOCKET NO.</b> 10191/3838	<b>SERIAL NO.</b> 10191/3838 To Be Assigned
	<b>APPLICANT(s)</b> HAAG, Wolfgang et al.	
	<b>FILING DATE</b> Filed Herewith	<b>GROUP</b> To Be Assigned

## U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE

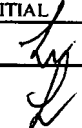
## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
						YES	NO
	WO 02 15404	February 21, 2002	PCT			X **	
	WO 96 31690	October 10, 1996	PCT			X **	
	JP 02 041029	February 9, 1990	Japan			X **	
	WO 01 10031	February 8, 2001	PCT			X **	
	EP 0 474 024	March 11, 1992	EPO			X **	
	DE 195 13 081	October 10, 1996	Germany			X *, **	

\* Mentioned in Specification.

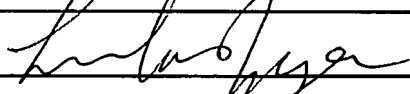
\*\* Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority).

## OTHER DOCUMENTS

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
	** Patent Abstracts of Japan, Vol. 014, no. 194 (E-0919), 20 April 1990 (1990-04-20).
	* "PC gesteuerte Messtechnik ..." ["PC-controlled measuring technology ..."] by Klaus Dembowski, Markt - und Technik Verlag, 1993. (No Abstract)

\* Mentioned in Specification.

\*\* Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority).

<b>EXAMINER</b> 	<b>DATE CONSIDERED</b> 9/25/07
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	